FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT	ATTY. DOCKET NO. PSU 00-2182C	09/677,203
AND TRADEMARK OFFICE	APPLICANT	İ
List of Information Cited by Applicant	Natan, et al.	
Page 1 of 2	FILING DATE	GROUP
	October 2. 2000	<u> </u>

	U.S. PATENT DOCUMENTS						
EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLS	SUB- CLS	FILE DATE
Prop	٨٨	5,571,726	11/5/96	Brooks, et al.			
	AD				ļ. <u>:</u> -		
	VC				 	 -	
·	AD			 		 	-
	Att		<u> </u>	 		├	
	AP					 	
	VC				 	 	-
	ΛII		 		 	-	
	A1 _		 		 	 	
	AJ.				 	 	
	AK	 				 	
	AL _		 				
 	AM					1	
	AN		 		'		
	, AU					1	
ļ	AQ.						

<u> </u>	_		FOREIGN PATENT D	OCUMENTS			r
EXAM. INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	ÇLS	SUB CLS	TRANS
	AR					<u> </u>	
	AS					_	 -
	AT						
	ΛÜ					ļ ——	ļ
	AY					\	ļ
	AW					 	
	ΑX						<u> </u>

		OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
PED	AY	Dermody, et al., Abstracts of Papers American Chemical Society, 1999, 217 (1-2); pANYL 137			
7.0	AZ	Reiss, et al., Abstracts Of Papers Of The American Chemical Society, 1998, 216, P173-COLL			
	AAA	Routkevitch, et al., J. Phys. Chem., 1996, 100(33):14037-47			
1	AAB	Sapp, et al., Chem. Mater., 1999, 11:1183-85			
PER	AAC	Martin, et al., Adv. Mater. 11:1021-25 (18 Aug 1999)			
	AAD				
EXAMINER	EXAMINER CHECKES DATE CONSIDERED 9 9 04				
=EXAMINE	*EXAMINER: Initial if reference considered whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				
conformance	conformance and not considered. Inches copy of this con-				